トノフラシ

Docket No. 10936-66

CERTIFICATE OF MAILING

I hereby certify that this paper being deposited with the United States Postal Service with sufficient Postage as first class mail in an envelope addressed to: Commissioner for Patents, Washington, DC 20231 or Coul / 2, 2002.

**PATENT** 

## IN THE UNITED STATES PATENT & TRADEMARK OFFICE PROPINET 1200 PC

Applicant:

Hideki Kitamura et al

Paper No.:

Serial No.:

10/019,858

Group Art Unit:

1752

Filing Date:

November 9, 2001

Examiner:

For:

Semiconductive Polyvinylidene Fluoride Resin Composition

## **INFORMATION DISCLOSURE STATEMENT**

**Assistant Commissioner for Patents** Washington, DC 20231

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56 and 1.97-1.98, Applicants cite and submit copies of the references listed on the attached Form PTO-1449.

Applicants note that Japanese Reference No. 47-3535 corresponds with U.S. Patents Nos. 3,703,569 and 3,829,408 and Japanese Reference No. 51-111337 corresponds with U.S. Patent No. 4,013,531. English language abstracts of the remaining Japanese language references are provided.

Since the present Statement is submitted prior to issuance of a first Official Action, no statement or fee under 37 C.F.R. 1.97 is required.

Respectfully submitted,

Holly D. Kozlowski, Reg. No. 30,468

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LIST OF PATENTS AND PUBLICATIONS APPLICANT Hideki Kitamura et al												
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ac 4 0 1 3 5 3 1 Mar. 22, 1977 Nakamura et al  FOREIGN PATENT DOCUMENTS												
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	ac	51-	1	1	1	3	3	7	Oct. 1, 1976	Japan		
	ad	47-	3	8	3	5			Feb. 24, 1972	Japan		
	ае	51	3	2	3	3	()		Mar. 18, 19 <sup>-</sup> 6	Japan (w,/English abstract)		
	af	51-	1	1	()	6	5	8	Sep. 30, 1976	Japan 'w/English abstract)		
	.1g	54-	1	2	-	8	7	2	Oct. 4, 1979	Japan (w/English abstract)		
	ah	60-	1	7	7	()	6	4	Sep. 11, 1985	Japan /w/English abstract)		
	ai	61-	7	2	0	6	1		Apr. 14, 1986	Japan [w/English abstract)		
	aj	55-	2	6	9		3		Jul. 17, 1980	Japan [w/English abstract)		
	ak	8-	2	7	2	2	()	8	Oct. 18, 1996	Japan [w/English abstract)		
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	am	7_	()	()	3	1	()	()	Jan. 6, 1995	Japan (w./English abstract)		
	an	6-	3	2	9	8	6	1	Nov. 29, 1994	Japan [w,/English abstract)		
	ао	11-	0	2	9	6	[*-	8	Feb. 2, 1999	Japan (w,/English abstract)		
	ар	11-	3	2	3	()	5	21	Nov. 26, 1999	Japan (w/English abstract)		
OTHER ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)												

EXAMINER DATE CONSIDERED EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 779959.01